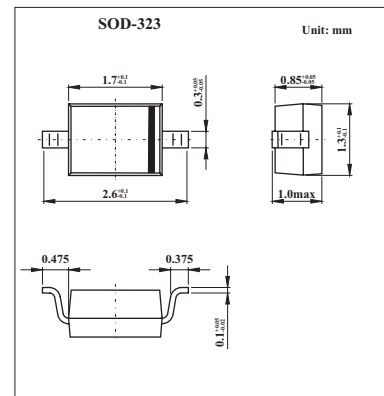


BAP51-03

■ Features

- Low diode capacitance
- Low diode forward resistance.

■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Min	Max	Unit
continuous reverse voltage	V_R		50	V
continuous forward current	I_F		50	mA
total power dissipation $T_s = 90^\circ\text{C}$	P_{tot}		500	mW
storage temperature	T_{stg}	-65	+150	$^\circ\text{C}$
junction temperature	T_j	-65	+150	$^\circ\text{C}$
thermal resistance from junction to soldering point	$R_{th\ j-s}$		120	K/W

■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
forward voltage	V_F	$I_F = 50\text{ mA}$		0.95	1.1	V
reverse voltage	V_R	$I_R = 10\ \mu\text{A}$	50			V
reverse current	I_R	$V_R = 50\text{ V}$			100	nA
diode capacitance	C_d	$V_R = 0; f = 1\text{ MHz}$		0.4		pF
		$V_R = 1\text{ V}; f = 1\text{ MHz}$		0.3	0.55	
		$V_R = 5\text{ V}; f = 1\text{ MHz}$		0.2	0.35	
diode forward resistance	r_D	$I_F = 0.5\text{ mA}; f = 100\text{ MHz}; \text{note 1}$		5.5	40	Ω
		$I_F = 1\text{ mA}; f = 100\text{ MHz}; \text{note 1}$		3.6	25	
		$I_F = 10\text{ mA}; f = 100\text{ MHz}; \text{note 1}$		1.5	5	
charge carrier life time	τ_L	when switched from $I_F = 10\text{ mA}$ to $I_R = 6\text{ mA}$; $R_L = 100\ \Omega$; measured at $I_R = 3\text{ mA}$		550		ns

Note

1. Guaranteed on AQL basis: inspection level S4, AQL 1.0.

■ Marking

Marking	A5
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